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2. Record Nr.	UNINA9910144714703321
Autore	Sarid Dror
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Descrizione fisica	1 online resource (312 p.)
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Soggetti	Scanning probe microscopy - Data processing Electronic books.
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Note generali	Description based upon print version of record.
Nota di bibliografia	Includes bibliographical references at the end of each chapters and index.
Nota di contenuto	Exploring Scanning Probe Microscopy with MATHEMATICA; Contents; Preface; 1 Introduction; 1.1 Style; 1.2 Mathematica Preparation; 1.2.1 General; 1.2.2 Example; 1.3 Recommended Books; 1.3.1 Mathematica Programming Language; 1.3.2 Scanning Probe Microscopies; 2 Uniform Cantilevers; 2.1 Introduction; 2.2 Bending Due to F(z); 2.2.1 General Equations; 2.2.2 Slope; 2.2.3 Angular Spring Constant; 2.2.4 Displacement; 2.2.5 Linear Spring Constant; 2.2.6 Numerical Example: Si; 2.2.7 Numerical Example: PtIr; 2.3 Buckling Due to F(x); 2.3.1 General Equations; 2.3.2 Slope; 2.3.3 Angular Spring Constant 4.1 Introduction4.2 Bending Due to F(z): Triangular Shape; 4.2.1 General Equations; 4.2.2 Slope; 4.2.3 Angular Spring Constant; 4.2.4 Displacement; 4.2.5 Linear Spring Constant; 4.2.6 Numerical Examples; 4.3 Buckling due to F(x): Triangular Shape; 4.3.1 General Equations; 4.3.2 Slope; 4.3.3 Angular Spring Constant; 4.3.4 Displacement; 4.3.5 Linear Spring Constant; 4.3.6 Numerical Examples; 4.4 Bending due to F(z): V Shape; 4.4.1 General Equations; 4.4.2 Slope; 4.4.3 Angular Spring Constant; 4.4.4 Displacement; 4.4.5 Linear Spring Constant; 4.4.6 Numerical Examples

6.2 Tip-Sample Interaction

Sommario/riassunto

This new and completely updated edition features not only an accompanying CD-ROM, but also a new applications section, reflecting the many breakthroughs in the field over the last few years. It provides a complete set of computational models that describe the physical phenomena associated with scanning tunneling microscopy, atomic force microscopy, and related technologies. The result is both a solid professional reference and an advanced-level text, beginning with the basics and moving on to the latest techniques, experiments, and theory. In the section devoted to atomic force microscopy,